

# Short Course on Microwave Measurements and Instrumentation

December 2-3, 2003  
Boulder, Colorado

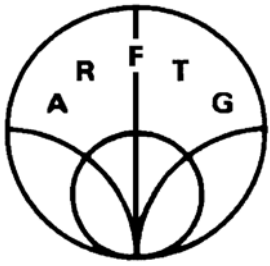


## PRELIMINARY AGENDA

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### Tuesday, December 2

- 7:30 a.m. – 8:00 a.m.    **Registration**
- 8:00 a.m. – 9:15 a.m.    **VNA Error Models and Calibration Methods**  
*Doug Rytting – Agilent*
- 9:15 a.m. – 9:50 a.m.    **RF Connectors and Transmission Lines**  
*John Juroshek – NIST*
- 9:50 a.m. – 10:20 a.m.   **Break**
- 10:20 a.m. – 11:00 a.m.   **VNA Uncertainty**  
*John Juroshek – NIST*
- 11:00 a.m. – 12:15 p.m.   **Microwave Power Measurements**  
*Tom Crowley – NIST*
- 12:15 p.m. – 1:30 p.m.    **Lunch**
- 1:30 p.m. – 2:00 p.m.    **Accurate On-Wafer Measurement**  
*Dylan Williams - NIST*
- 2:00 p.m. – 2:45 p.m.    **Introduction to Optoelectronic Measurements**  
*Paul Hale – NIST*
- 2:45 p.m. – 3:05 p.m.    **Break**
- 3:05 p.m. – 3:45 p.m.    **Practical Oscilloscope Measurements**  
*Tracy Clement – NIST*
- 3:45 p.m. – 5:00 p.m.    **Thermal Noise Measurements**  
*Jim Randa – NIST*



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# **NIST**

## **PRELIMINARY AGENDA**

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### **Wednesday, December 3**

- 8:00 a.m. – 8:50 a.m.    **Uncertainty Analysis**  
*Nick Ridler – NPL*
- 8:50 a.m. – 9:35 a.m.    **Phase Noise Measurements**  
*Ed Godshalk – Maxim*
- 9:35 a.m. – 10:15 a.m.    **Large-Signal Network Analysis – Part I**  
*Jan Verspecht – Jan Verspecht bvba*
- 10:15 a.m. – 10:30 a.m.    **Break**
- 10:30 a.m. – 11:15 p.m.    **Large-Signal Network Analysis – Part II**  
*Jan Verspecht – Jan Verspecht bvba*
- 11:15 a.m. – 12:00 p.m.    **EMC in the Measurement Laboratory**  
*Howard Reader – University of Stellenbosch*